

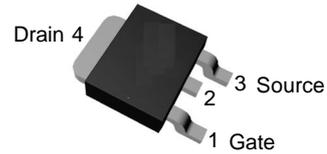


P-Channel Enhancement Mode MOSFET

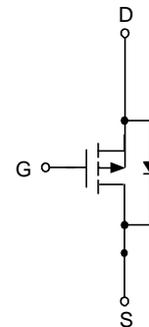
Features

- -60V/-15A,
 $R_{DS(ON)} = 93m\Omega(\text{max.}) @ V_{GS} = -10V$
 $R_{DS(ON)} = 128m\Omega(\text{max.}) @ V_{GS} = -4.5V$
- Reliable and Rugged
- Lead Free and Green Devices Available (RoHS Compliant)
- 100% UIS + R_g Tested

Pin Description



Top View of TO-252-3



P-Channel MOSFET

Applications

- Power Management in Notebook Computer, Portable Equipment and Battery Powered Systems.

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**Absolute Maximum Ratings** ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Rating	Unit
Common Ratings ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)			
V_{DSS}	Drain-Source Voltage	-60	V
V_{GSS}	Gate-Source Voltage	± 25	
T_J	Maximum Junction Temperature	150	$^\circ\text{C}$
T_{STG}	Storage Temperature Range	-55 to 150	
I_S	Diode Continuous Forward Current	$T_C = 25^\circ\text{C}$ -10	A
I_D	Continuous Drain Current	$T_C = 25^\circ\text{C}$ -15	
		$T_C = 100^\circ\text{C}$ -9.5	
I_{DM}	Pulsed Drain Current	$T_C = 25^\circ\text{C}$ -62*	
P_D	Maximum Power Dissipation	$T_C = 25^\circ\text{C}$ 44.6	W
		$T_C = 100^\circ\text{C}$ 17.9	
$R_{\theta JC}$	Thermal Resistance-Junction to Case	Steady State 2.8	$^\circ\text{C/W}$
I_D	Continuous Drain Current	$T_A = 25^\circ\text{C}$ -5.8	A
		$T_A = 70^\circ\text{C}$ -4.6	
P_D	Maximum Power Dissipation	$T_A = 25^\circ\text{C}$ 6.25	W
		$T_A = 70^\circ\text{C}$ 4	
$R_{\theta JA}$	Thermal Resistance-Junction to Ambient	$t \leq 10\text{s}$ 20	$^\circ\text{C/W}$
		Steady State 55	
I_{AS}^a	Avalanche Current, Single pulse ($L=0.1\text{mH}$)	19	A
E_{AS}^a	Avalanche Energy, Single pulse ($L=0.1\text{mH}$)	18	mJ

Note * : Current limited by bond wire.

Note a : UIS tested and pulse width are limited by maximum junction temperature 150°C (initial temperature $T_J = 25^\circ\text{C}$).

**Electrical Characteristics** ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
Static Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_{DS}=-250\mu A$	-60	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-48V, V_{GS}=0V$	-	-	-1	μA
		$T_J=85^\circ\text{C}$	-	-	-30	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_{DS}=-250\mu A$	-1	-2	-3	V
I_{GSS}	Gate Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	± 100	nA
$R_{DS(ON)}^b$	Drain-Source On-state Resistance	$V_{GS}=-10V, I_{DS}=-5.8A$	-	73	93	m Ω
		$V_{GS}=-4.5V, I_{DS}=-3.5A$	-	93	128	
Diode Characteristics						
V_{SD}^b	Diode Forward Voltage	$I_{SD}=-1A, V_{GS}=0V$	-	-0.7	-1	V
t_{rr}^c	Reverse Recovery Time	$I_{SD}=-5.8A,$ $di_{SD}/dt=100A/\mu s$	-	22	-	ns
Q_{rr}^c	Reverse Recovery Charge		-	23	-	nC
Dynamic Characteristics^c						
R_G	Gate Resistance	$V_{GS}=0V, V_{DS}=0V, F=1\text{MHz}$	-	10	20	Ω
C_{iss}	Input Capacitance	$V_{GS}=0V,$ $V_{DS}=-30V,$ Frequency=1.0MHz	-	530	-	μF
C_{oss}	Output Capacitance		-	66	-	
C_{rss}	Reverse Transfer Capacitance		-	36	-	
$t_{d(ON)}$	Turn-on Delay Time	$V_{DD}=-30V, R_L=30\Omega,$ $I_{DS}=-1A, V_{GEN}=-10V,$ $R_G=6\Omega$	-	9	-	ns
t_r	Turn-on Rise Time		-	6	-	
$t_{d(OFF)}$	Turn-off Delay Time		-	36	-	
t_f	Turn-off Fall Time		-	25	-	
Gate Charge Characteristics^c						
Q_g	Total Gate Charge	$V_{DS}=-30V, V_{GS}=-10V,$ $I_{DS}=-5.8A$	-	12	-	nC
Q_{gs}	Gate-Source Charge		-	1.5	-	
Q_{gd}	Gate-Drain Charge		-	3.3	-	

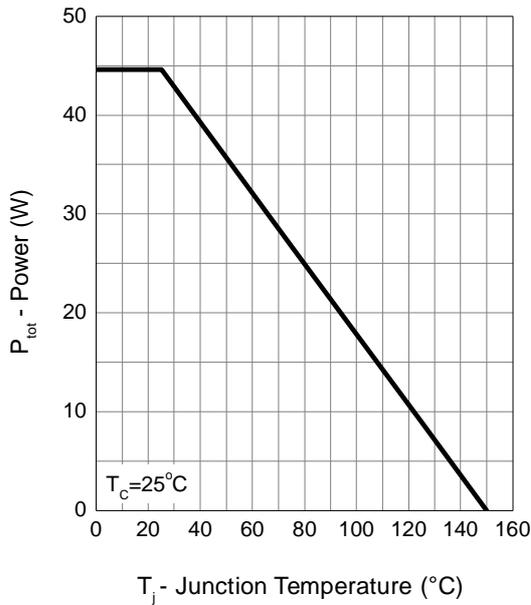
Note b : Pulse test ; pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$.

Note c : Guaranteed by design, not subject to production testing.

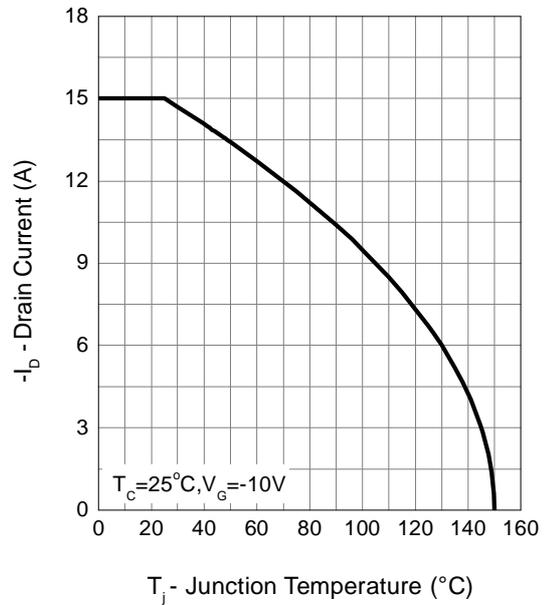


Typical Operating Characteristics

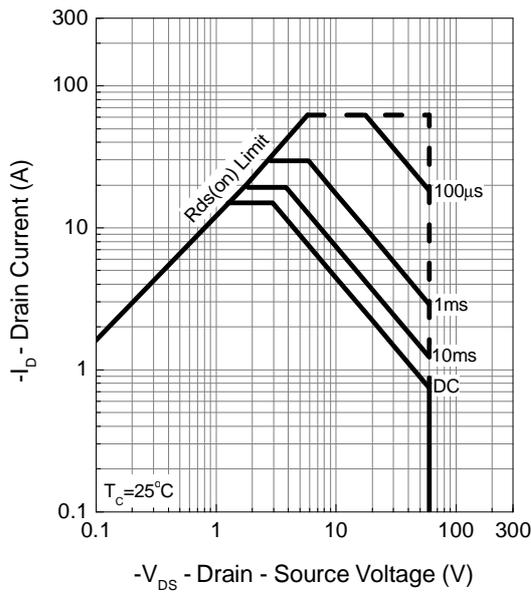
Power Dissipation



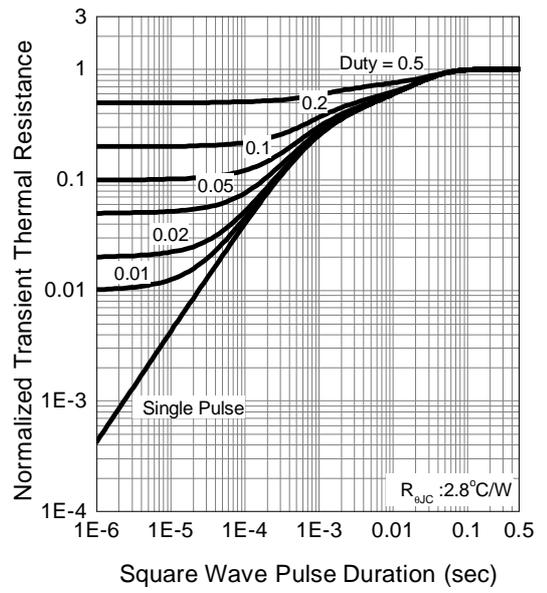
Drain Current



Safe Operation Area



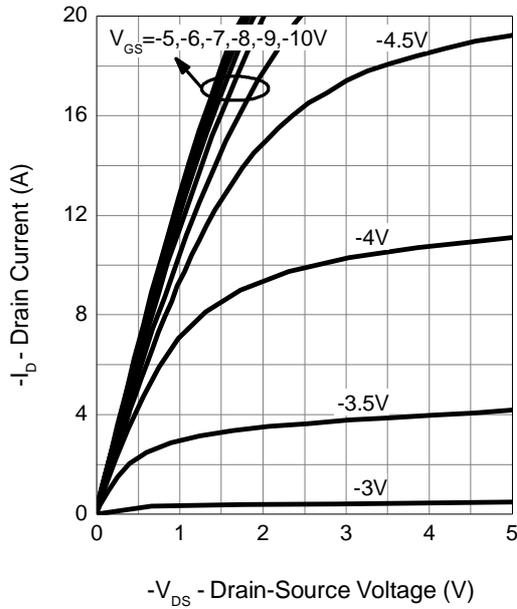
Thermal Transient Impedance



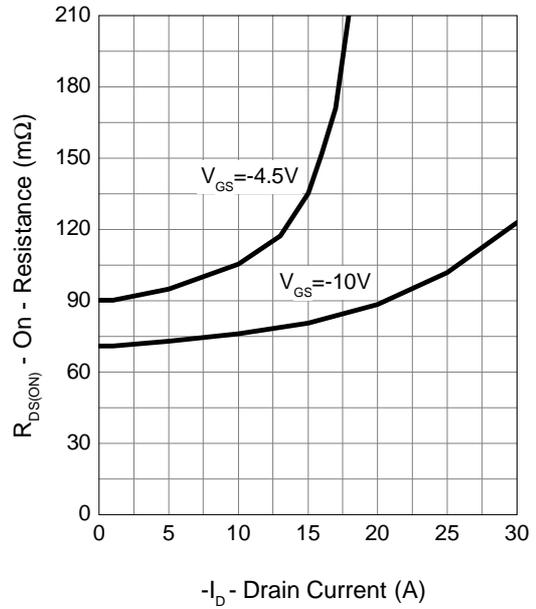


Typical Operating Characteristics (Cont.)

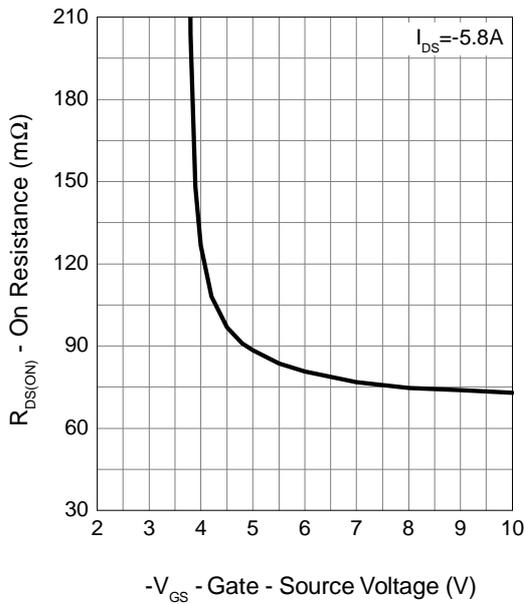
Output Characteristics



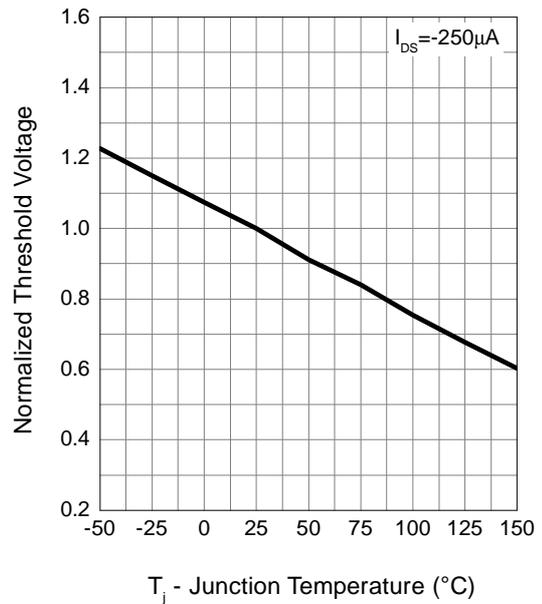
Drain-Source On Resistance



Gate-Source On Resistance



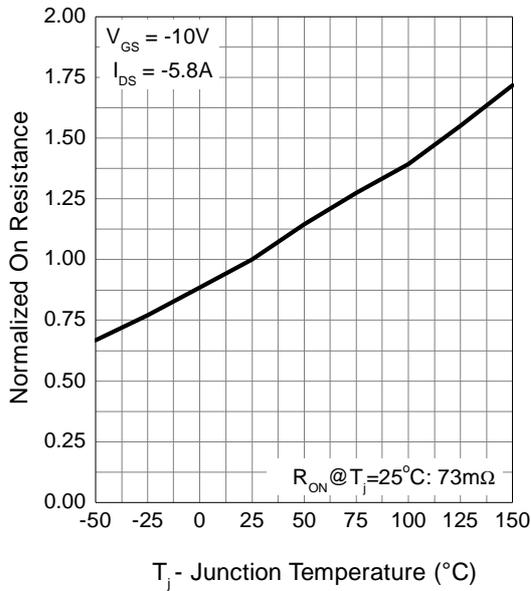
Gate Threshold Voltage



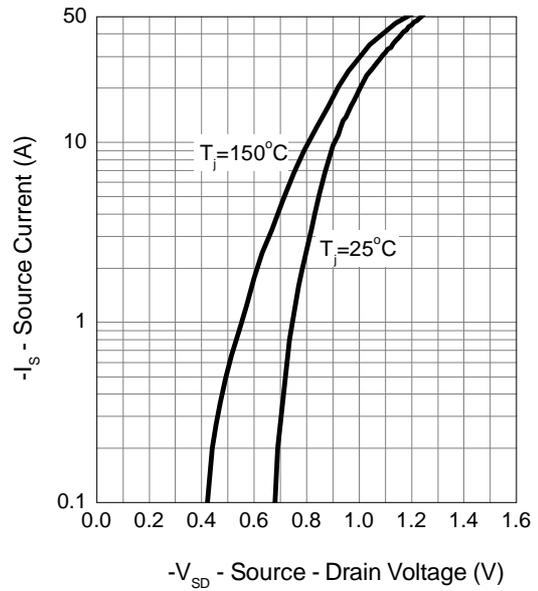


Typical Operating Characteristics (Cont.)

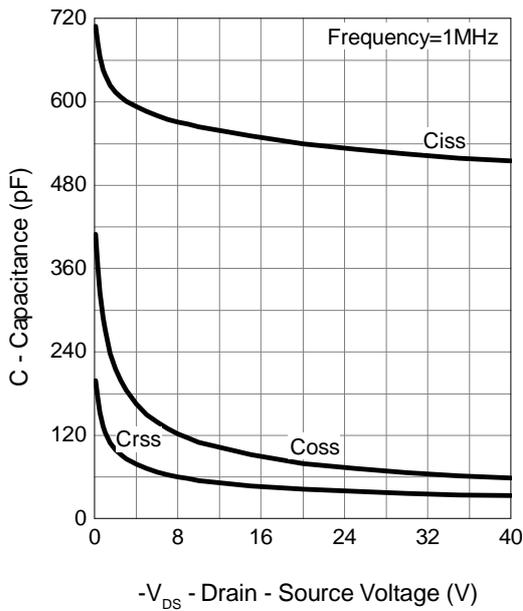
Drain-Source On Resistance



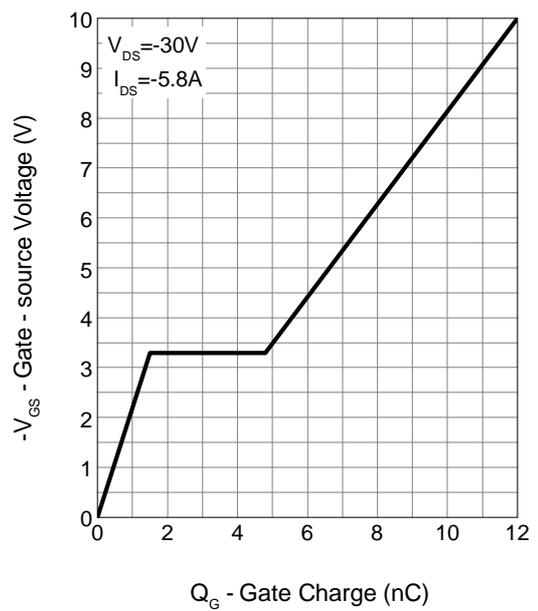
Source-Drain Diode Forward



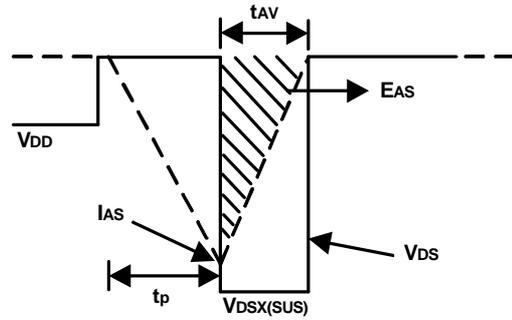
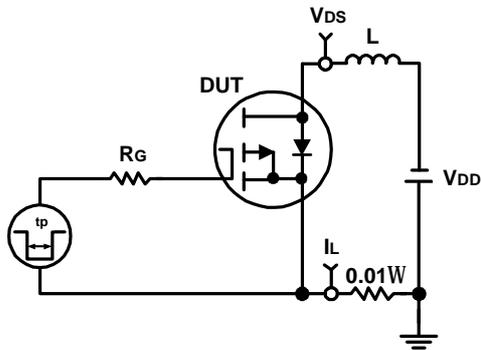
Capacitance



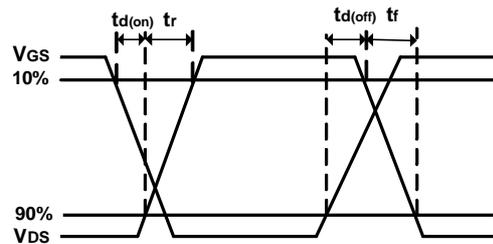
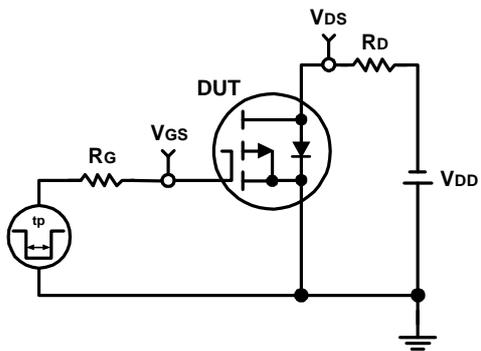
Gate Charge



Avalanche Test Circuit and Waveforms



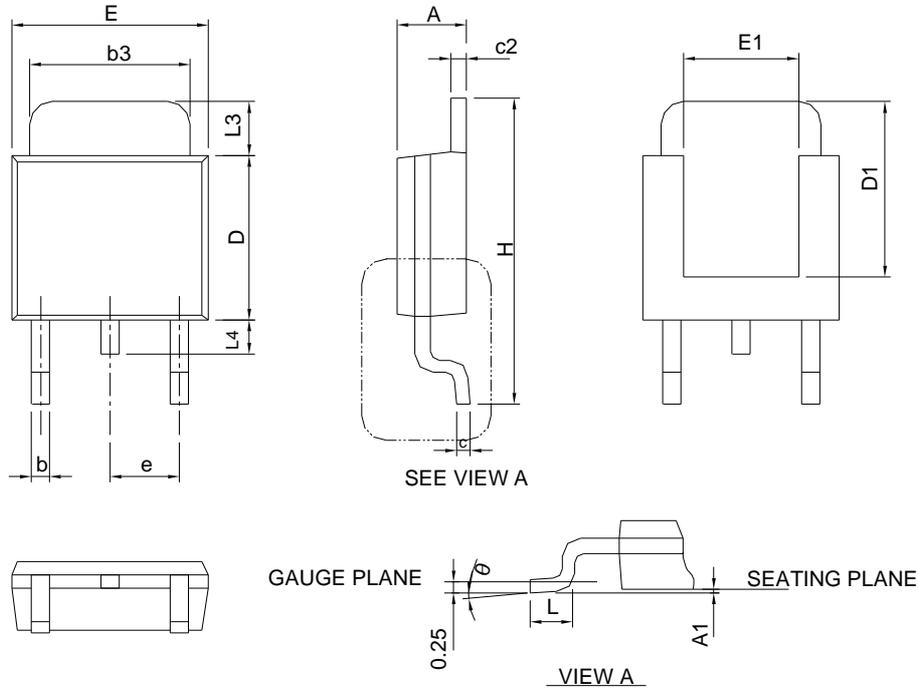
Switching Time Test Circuit and Waveforms





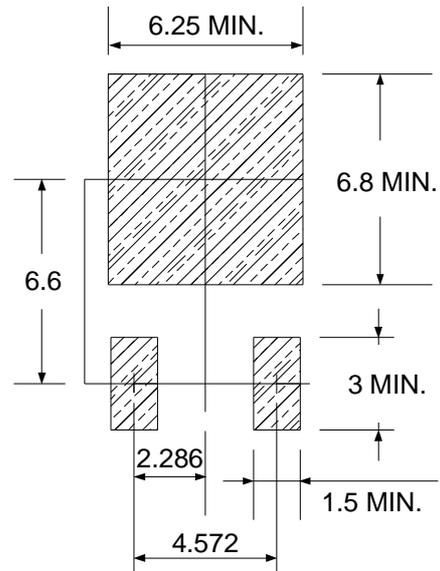
Package Information

TO-252-3



DIMENSIONS	TO-252-3			
	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A	2.18	2.39	0.086	0.094
A1	-	0.13	-	0.005
b	0.50	0.89	0.020	0.035
b3	4.95	5.46	0.195	0.215
c	0.46	0.61	0.018	0.024
c2	0.46	0.89	0.018	0.035
D	5.33	6.22	0.210	0.245
D1	4.57	6.00	0.180	0.236
E	6.35	6.73	0.250	0.265
E1	3.81	6.00	0.150	0.236
e	2.29 BSC		0.090 BSC	
H	9.40	10.41	0.370	0.410
L	0.90	1.78	0.035	0.070
L3	0.89	2.03	0.035	0.080
L4	-	1.02	-	0.040
θ	0°	8°	0°	8°

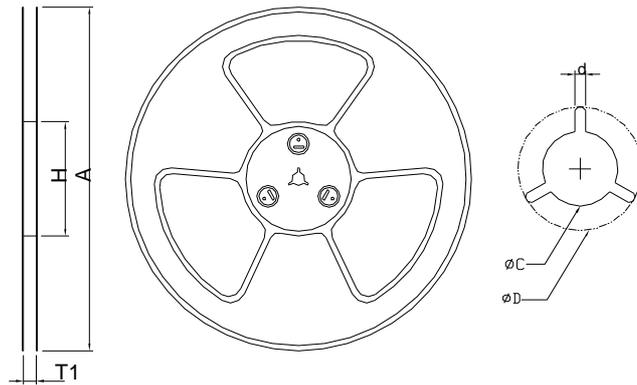
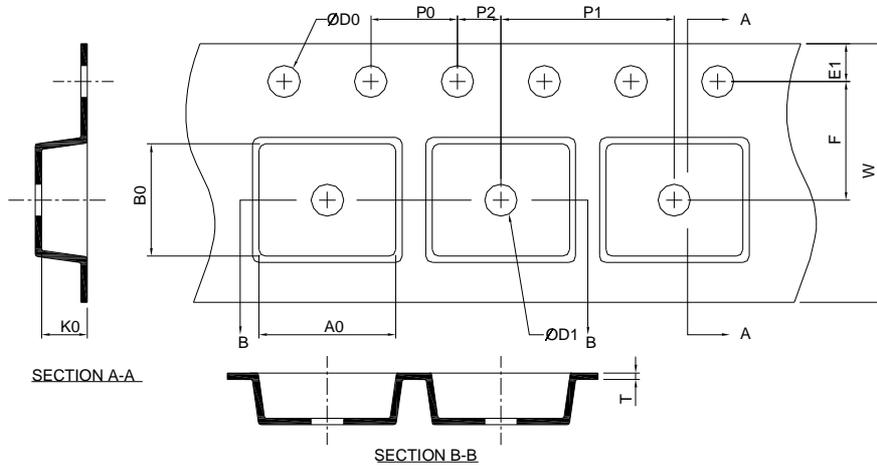
RECOMMENDED LAND PATTERN



UNIT: mm

Note : Follow JEDEC TO-252 .

Carrier Tape & Reel Dimensions

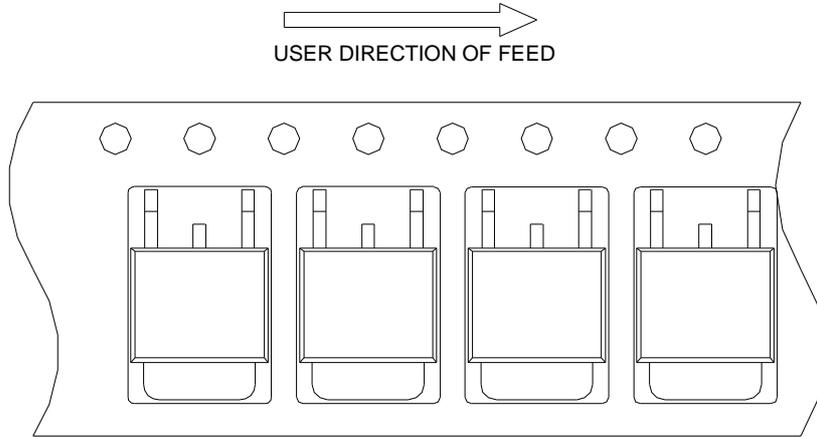


Application	A	H	T1	C	d	D	W	E1	F
TO-252-3	330.0±2.00	50 MIN.	16.4+2.00 -0.00	13.0+0.50 -0.20	1.5 MIN.	20.2 MIN.	16.0±0.30	1.75±0.10	7.50±0.05
	P0	P1	P2	D0	D1	T	A0	B0	K0
	4.0±0.10	8.0±0.10	2.0±0.05	1.5+0.10 -0.00	1.5 MIN.	0.6+0.00 -0.40	6.80±0.20	10.40±0.20	2.50±0.20

(mm)

Taping Direction Information

TO-252-3



Classification Profile

